

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination SAH, ADAM D.	
		Examiner Sargon N Nano	Art Unit 2157	Page 1 of 1

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	C	US-6,597,393	07-2003	Kato et al.	348/211.99
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	M	US-			

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**NON-PATENT DOCUMENTS**

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